Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/722,155	SANA ET AL.
Examiner	Art Unit
Young J. Kim	1637

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEARCH	SIRATEGY)
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	9/28/2007	YJK
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